EC2600TTS-36.864M



Temperature Cycling

Vibration

T TS -36.864M

L Nominal Frequency 36.864MHz

Pin 1 Connection

Tri-State (High Impedance) **tty Cycle** ±5(%)

Frequency Tolerance/Stability _____ ±100ppm Maximum Operating Temperature Ran -10°C to +70°C

EC26 00

	L Duty Cy
ge —	50 ±5(%

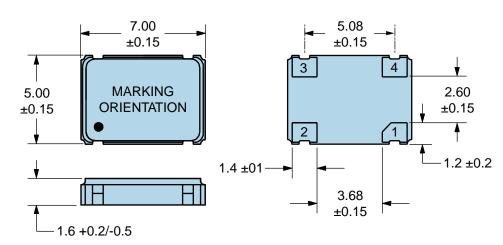
ELECTRICAL SPECIFICA	ELECTRICAL SPECIFICATIONS				
Nominal Frequency	36.864MHz				
Frequency Tolerance/Stability	±100ppm Maximum (Inclusive of all conditions: Calibration Tolerance at 25°C, Frequency Stability over the Operating Temperature Range, Supply Voltage Change, Ouput Load Change, First Year Aging at 25°C, Shock, and Vibration)				
Operating Temperature Range	-10°C to +70°C				
Supply Voltage	3.3Vdc ±10%				
Input Current	18mA Maximum				
Output Voltage Logic High (Voh)	90% of Vdd Minimum (IOH=-8mA)				
Output Voltage Logic Low (Vol)	10% of Vdd Maximum (IOL=+8mA)				
Rise/Fall Time	3nSec Maximum (Measured at 20% to 80% of waveform)				
Duty Cycle	50 ±5(%) (Measured at 50% of waveform)				
Load Drive Capability	15pF Maximum				
Output Logic Type	CMOS				
Pin 1 Connection	Tri-State (High Impedance)				
Tri-State Input Voltage (Vih and Vil)	+0.7Vdd Minimum or No Connect to Enable Output, +0.3Vdd Maximum to Disable Output (High Impedance)				
Standby Current	10µA Maximum (Disabled Output: High Impedance)				
RMS Phase Jitter	1pSec Maximum (12kHz to 20MHz offset frequency)				
Start Up Time	10mSec Maximum				
Storage Temperature Range	-55°C to +125°C				
ENVIRONMENTAL & MEC	HANICAL SPECIFICATIONS				
ESD Susceptibility	MIL-STD-883, Method 3015, Class 1, HBM: 1500V				
Fine Leak Test	MIL-STD-883, Method 1014, Condition A				
Flammability	UL94-V0				
Gross Leak Test	MIL-STD-883, Method 1014, Condition C				
Mechanical Shock	MIL-STD-883, Method 2002, Condition B				
Moisture Resistance	MIL-STD-883, Method 1004				
Moisture Sensitivity	J-STD-020, MSL 1				
Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K				
Resistance to Solvents	MIL-STD-202, Method 215				
Solderability	MIL-STD-883, Method 2003				
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MIL-STD-883, Method 1010, Condition B

MIL-STD-883, Method 2007, Condition A

EC2600TTS-36.864M

MECHANICAL DIMENSIONS (all dimensions in millimeters)



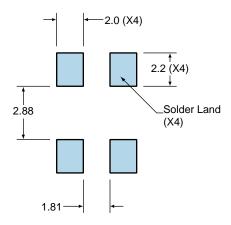
ECLIPTEK CORPORATION		
PIN	CONNECTION	
1	Tri-State	
2	Ground/Case Ground	
3	Output	
4	Supply Voltage	
LINE	MARKING	

NE	WARKING
	ECLIPTEK
	36.864M
	XXYZZ XX=Ecliptek Manufacturing Code Y=Last Digit of the Year ZZ=Week of the Year

1 2 3

Suggested Solder Pad Layout

All Dimensions in Millimeters



All Tolerances are ±0.1

EC2600TTS-36.864M



OUTPUT WAVEFORM & TIMING DIAGRAM



Test Circuit for CMOS Output



Note 1: An external 0.1μ F low frequency tantalum bypass capacitor in parallel with a 0.01μ F high frequency ceramic bypass capacitor close to the package ground and V_{DD} pin is required.

Note 2: A low capacitance (<12pF), 10X attenuation factor, high impedance (>10Mohms), and high bandwidth (>300MHz) passive probe is recommended.

Note 3: Capacitance value \dot{C}_L includes sum of all probe and fixture capacitance.



Recommended Solder Reflow Methods



High Temperature Infrared/Convection

EC2600TTS-36.864M

. .	
T _s MAX to T _L (Ramp-up Rate)	3°C/second Maximum
Preheat	
- Temperature Minimum (T _s MIN)	150°C
- Temperature Typical (T _s TYP)	175°C
 Temperature Maximum (T_s MAX) 	200°C
- Time (t _s MIN)	60 - 180 Seconds
Ramp-up Rate (T⊾ to T _P)	3°C/second Maximum
Time Maintained Above:	
- Temperature (T∟)	217°C
- Time (t∟)	60 - 150 Seconds
Peak Temperature (T _P)	260°C Maximum for 10 Seconds Maximum
Target Peak Temperature (T _P Target)	250°C +0/-5°C
Time within 5°C of actual peak (t _P)	20 - 40 seconds
Ramp-down Rate	6°C/second Maximum
Time 25°C to Peak Temperature (t)	8 minutes Maximum
Moisture Sensitivity Level	Level 1
Additional Notes	Temperatures shown are applied to body of device.



Recommended Solder Reflow Methods

EC2600TTS-36.864M



Low Temperature Infrared/Convection 240°C

T_s MAX to T_L (Ramp-up Rate)	5°C/second Maximum
Preheat	
- Temperature Minimum (T _s MIN)	N/A
- Temperature Typical (T _s TYP)	150°C
- Temperature Maximum (T _s MAX)	N/A
- Time (t _s MIN)	60 - 120 Seconds
Ramp-up Rate (T⊾ to T _P)	5°C/second Maximum
Time Maintained Above:	
- Temperature (T∟)	150°C
- Time (t∟)	200 Seconds Maximum
Peak Temperature (T _P)	240°C Maximum
Target Peak Temperature (T _P Target)	240°C Maximum 1 Time / 230°C Maximum 2 Times
Time within 5°C of actual peak (t_p)	10 seconds Maximum 2 Times / 80 seconds Maximum 1 Time
Ramp-down Rate	5°C/second Maximum
Time 25°C to Peak Temperature (t)	N/A
Moisture Sensitivity Level	Level 1
Additional Notes	Temperatures shown are applied to body of device.

Low Temperature Manual Soldering

185°C Maximum for 10 seconds Maximum, 2 times Maximum. (Temperatures shown are applied to body of device.)

High Temperature Manual Soldering

260°C Maximum for 5 seconds Maximum, 2 times Maximum. (Temperatures shown are applied to body of device.)